

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of	:	Customer Number: 89518
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CHEN, Hui-Mei, et al.	:	Confirmation Number: 3341
	:	
Application No.: 10/786,807	:	Group Art Unit: 2822
	:	
Filed: February 25, 2004	:	Examiner: AU, Bac H.
	:	
For: METHOD FOR IMPROVING SEMICONDUCTOR WAFER TEST ACCURACY	:	

RESPONSE/AMENDMENT

Mail Stop Amendment
Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

In response to the non-final Office Action dated September 30, 2011, entry and consideration of the following amendments and remarks are respectfully requested.

Amendments to the Claims are reflected in the listing of claims which begins on page 2 of this paper.

Remarks/Arguments begin on page 5 of this paper.

An **Appendix** showing the status of related cases is attached after the last page of this paper.